



Sheet 1 of 2

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. H-1027-02	SERIAL NO. <b>10/774,371</b>
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APPLICANT  
Y. TAKAHASHI et al

FILING DATE  
February 10, 2004

GROUP  
**1762**

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
AB	AA 5,738,927	04/1998	Nakamura et al			
	AB 6,080,476	06/2000	Kanbe et al			
	AC 5,815,343	09/1998	Ishikawa et al			
	AD 6,168,861	01/2001	Chen et al			
AB	AE 5,939,202	08/1999	Ataka et al			
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AB	AL 10-269548	10/9/98	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AM					<input type="checkbox"/>	<input type="checkbox"/>
	AN					<input type="checkbox"/>	<input type="checkbox"/>
	AO					<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, etc.)

AB	AR	JOURNAL OF MAGNETISM AND MAGNETIC MATERIALS, 152 (1996), "Effects of Pt addition on the magnetic and crystallographic properties of Co-Cr-Pt thin-film media", A. Ishikawa et al, pp. 265-273.
AB	AS	Nakatani, Y. and Hayashi, N., IEEE Trans. Mag., 34(4), 1998, 1618-1620.
AB	AT	Ikeda, Y., Sonobe, Y., Zeltzer, G., Yen, B., Takano, K., Do, H., Fullerton, E., and Rice, P., IEEE Trans. Mag., 37(4), 2001, 1583, 1585.

EXAMINER /Alain Bashore/ (01/03/2007)

DATE CONSIDERED

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<b>LIST OF DOCUMENTS CITED BY APPLICANT</b> <i>(Use several sheets if necessary)</i>				APPLICANT Y. TAKAHASHI et al			
				FILING DATE 2/10/04	GROUP <u>1773</u> <u>1762</u>		
<b>U.S. PATENT DOCUMENTS</b>							
* EXAMINER INITIAL	AA	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE <i>(If Appropriate)</i>
	AB						
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<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
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	AP						<input type="checkbox"/> <input type="checkbox"/>
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
AB	AR	Lu, B., Klemmer, T., Khizroev, S., Howard, J., Litvinov, D., Roy, A., and Laughlin, D., IEEE Trans. Mag., 37(4), 2001, 1319-1321.					
AB	AS	Yamanaka, K., Hamamoto, T., Nakano, Y. and Miura, M., IEEE Trans. Mag., 37(4), 2001, 1599-1601.					
AB	AT	Futamoto, M., Honda, Y., Hirayama, Y., Itoh, K., Ide, H., and Maruyama, Y., IEEE Trans. Mag., 32(5), 1996, 3789-3794.					
EXAMINER /Alain Bashore/ (01/03/2007)				DATE CONSIDERED			
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